



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Michael E. Fossey et al. Art Unit : 2877
Serial No. : 10/601,698 Examiner : Unknown
Filed : June 24, 2003
Title : WAFER INSPECTION SYSTEM FOR DISTINGUISHING PITS AND
PARTICLES

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicant submits the references listed on the attached form PTO-1449. A copy of a communication from a foreign patent office in a counterpart application is also enclosed.

Submitted herewith is an English translation of the following foreign language references, or portions thereof:

Desig. ID	Source
AL	Japan 63-143831 A: English Abstract
AM	Japan 63-298035 A: English Abstract
AN	Japan 6-242012 A: English Abstract

This statement is being filed before the receipt of a first Office action on the merits.
Please apply any charges or credits to Deposit Account No. 06-1050.

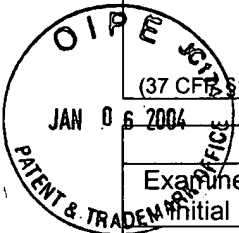
Respectfully submitted,

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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 03351-009005	Application No. 10/601,698
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR § 1.98(b))		Applicant Michael E. Fossey et al.	
		Filing Date June 24, 2003	Group Art Unit 2877



U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL	63143831	6/16/1988	Japan			X	
	AM	63298035	12/5/1988	Japan			X	
	AN	06242012	9/2/1994	Japan			X	
	AO	WO96/27786	2/9/1999	WPO				X
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	